

# High-speed Spectroscopic Ellipsometer [UNECS Series]

UNECS series is a kind of spectroscopic ellipsometers to measure the refractive index and thickness of the thin film quickly and accurately. It adopts an unique measurement method, and realizes the compact size and high-speed measurement. It has a strong products line, such as the portable type, the automatic stage type, and the built-in type etc.



**UNECS-Portable** 



UNECS-3000A

#### Features

> High-speed Measurement :

The snapshot measurement method is realized and the high-speed measurement is 20ms per point.

> Visible Spectral Range :

The spectral wavelength range can be selected. The standard type is  $530nm \sim 750nm$  and the visible spectral type is  $380nm \sim 760nm$ .

> Compact Sensor Unit :

The sensor unit is light-weighted and very compact. It consists of an optical element that does not have any rotating mechanism. In addition, there is no need for any periodic maintenance.

Strong Product-line :

There is a strong products line with the portable type, the manual/ automatic stage type, the built-in type and the large substrate type etc.

#### Applications

Measurement for transparent or semi-transparent thin films thickness(D), reflective index(N) and extinction coefficient(K). (Oxide film, nitride film, photo-resist film, ITO film, etc.)



Mode: High-speed Minimum: 98.422 Uniformity: 0.419 Start Time: 2013/05/27 10:41:59 Maximum: 99.251 Average: 98.773 STD.DEV: 0.158 End Time: 2013/05/27 10:44:12

> $\langle$  UNECS-3000A 2D Color Map  $\rangle$ Si0<sub>2</sub> film on  $\phi$ 300mm Wafer Measurement Time : 133sec/169points

Film Thickness



## UNECS-Portable(Portable)



With stage



#### Compact Light-weighted Portable Type

Features

The weight of the measurement unit is only 2.2kg. It is easy to be carried for vacuum equipments site acceptance test and can measure large size samples by detaching its sample stage and putting it directly on samples.

Specifications					
Navelength Range 530~750nm or 380~760nm					
$\phi$ 1mm or $\phi$ 0.3mm					
70°					
1 <i>σ</i> =0.1nm					
1nm~2µm					
Sampling: 20ms~3000ms Analyzing time: 300ms					
Fixed Stage (< $\phi$ 150mm, detachable)					
Laptop PC including analysis software					

#### Configuration

- Measurement unit (including fixed stage).
- Control box.
- Light source unit.
- > Control PC (Laptop type) and operation manual (CD).

# UNECS-1500M(Manual Stage)



Manual R- $\theta$  stage

#### Manual Stage Type for $\phi$ 150mm Samples

#### Features

It is easy to locate measurement points by the easy-to-use manual  $R-\theta$  stage.

Specifications						
Wavelength Range	530~750nm or 380~760nm					
Spot Size	$\phi$ 1mm or $\phi$ 0.3mm					
Angle of Incidence	70°					
Film Thickness Repeatability	1 <i>σ</i> =0.1nm					
Film Thickness Measurement Range	1nm~2µm					
Measurment Time	Sampling: 20ms~3000ms Analyzing: 300ms					
Sample Stage	Manual R- $\theta$ stage for $\phi$ 150mm sample					
Control PC	Laptop PC including analysis software					

#### Configuration

- > Measurement unit (including manual stage and Control box).
- Light source unit.
- Control PC (Laptop type) and operation manual (CD).

### UNECS-1500A/2000A/3000A(Auto Mapping Stage)



#### UNECS-1500A/2000A



UNECS-3000A

#### Automatic Stage Type with Mapping Function

Features

3 models are available for  $\phi$ 150, 200 and 300mm samples. Auto mapping R- $\theta$  stage and auto focus function make it possible to measure film thickness of entire sample surface and dispay film thickness distribution by color map.

1500A 530~750nm or 3	2000A	3000A			
530~750nm or 3					
	530~750nm or 380~760nm				
$\phi$ 1mm or $\phi$ 0.3mm					
70°					
1σ=0.1nm					
1nm~2µm					
Sampling: 20ms~3000ms Analyzing: 300ms					
φ150mm	φ200mm	<i>ф</i> 300mm			
200	200	2,000			
Laptop PC including analysis software					
	$\phi$ 1mm or $\phi$ 0.3m 70° 1 $\sigma$ =0.1nm 1m~2 $\mu$ m Sampling: 20ms~ $\phi$ 150mm 200 Laptop PC includi	$\phi$ 1mm or $\phi$ 0.3mm 70° 1 $\sigma$ = 0.1nm 1m~2µm Sampling: 20ms~3000ms Analyzin $\phi$ 150mm $\phi$ 200m 200 200 Laptop PC including analysis softwa			

#### Configuration

- > Measurement unit.
- ➤Control unit.
- > Control PC (Laptop type) and operation manual (CD).

## UNECS-1M(Integration)



#### **Built-in Type for System Integration**

#### Features

The light-weighted and compact design make it possible to be integrated into various equipments. It is suitable for both of vacuum and atmospheric pressure environments.

Specifications						
Wavelength Range 530~750nm or 380~760nm						
Spot Size	$\phi$ 1mm or $\phi$ 0.3mm					
Angle of Incidence	70°					
Film Thickness Repeatability	1 <i>σ</i> =0.1nm					
Film Thickness Measurement Range	1nm~2µm					
Measurment Time	Sampling: 20ms~3000ms Analyzing: 300ms					
Installation Environment	Atmosphere or vacuum					
Configuration						

- > Measurement unit.
- Control box.
- ► Light source unit.
- > Operation manual (CD).
- > Analysis software (CD).

[For large size substrate] In addition to these standard models, the model for large size substrate (G6) is available. Please contact us for more information.



# **High-speed Spectroscopic Ellipsometer [UNECS Series]**

Specifications								
Model name		UNECS-Portable	UNECS-1500M	UNECS-1500A	UNECS-2000A	UNECS-3000A		
Measurment method	t	Spectroscopic ellipsometry						
Film for measureme	nt *0	Transparent film and semitransparent film						
Wavelength		530~750nm or 380~760nm						
Light source		Halogen or xenon lamp						
Spot size		φ1mm or φ0.3mm						
Multilayer film measurement		Film thickness : Max 6 layer	Film thickness : Max 6 layer					
		Film thickness and optical parameter : 1 layer (Only the top layer)						
Angle of incidence		70°						
Film thickness Repeata	bility *2*3*4	0.1nm						
Film thickness measuren	nent range *3	1nm~2µm						
Scan time *3	Sampling	20~3000ms (setting is possible)						
	Analyzing	300ms						
Sample stage size		Fixed Stage ( $<\phi$ 150mm, detachable)	φ150mm		φ200mm	<b>Ø</b> 300mm		
Stage travel range	R	-	90mm Manual	0~75mm Programmable(Resolution 0.1mm)	0~100mm Programmable(Resolution 0.1mm)	0~150mm Programmable(Resolution 0.1mm)		
	θ	-	360° Manual	0~359.9° Programmble(Resolution 0.1°)				
Automatic measurable point -		-		200 (Option:2,000)	200 (Option:2,000)	2,000		
Focus(Z-axis)adjustr	nent	Manual		Auto				
Maximum sample th	iicness	8mm	10mm	30mm				
Maximam sample w	eight	10kg						
Analitical function	ical function ①Ψ ( λ ), Δ ( λ )measurement ② Calculation of film thickness(D), reflective index(N), extinction coefficient(K) ② 2D color mapping (Option:3D mapping)							
Material data file		Various such as oxide or nitride film (editing	and adding available)	· · · · · · · · · · · · · · · · · · ·				
Sample view camera	a	-		Option				
Contorol PC		Laptop PC Windows 7						
Dimentions W×D×I	н	Measurement unit :220mm×268mm×244mm	Measurement unit :300mm×400mm×384mm	Main unit :400mm×525mm×370mm		Main unit :450mm×620mm×370mm		
		(Not include PC, controller, the light source)	(Not include PC and light source)	Controller :204mm×500mm×509mm				
Weight		Measurement unit :2.2kg	Measurement unit :10.3kg	Main unit :24kg		Main unit :31kg		
		Stage :1.3kg		Controller :19kg				
Utility Power		AC100 /200V Max 3A 50/60Hz		AC100 /200V Max 6A 50/60Hz				
	Vacuum	-		75kPa (When using vacuum chuck)				
Operation Enviroment	Temperature	25±5[°C]						
	Humidity	65 [%RH] or less (Non condensing)						

%1 The semitransparent film is the upper bound in the measurement film thickness. %2 When only the film thickness value is assumed to be a fitting parameter, and the SiO<sub>2</sub> film (about 100 nm) on the Si substrate is measured. 3 When SiO<sub>2</sub> single-layer film on Si wafer is measured. 3 4 Standard deviation (1σ) when measuring it continuousness ten times.

Option

- Standard sample (100nm SiO<sub>2</sub>/Si)
- > Operation manual (normal or clean paper)
- High density mapping for 2,000 points (for 1500A/2000A)
- > 3D color map (for 1500A/2000A/3000A)
- Sample observation camera (for 1500A/2000A/3000A)



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